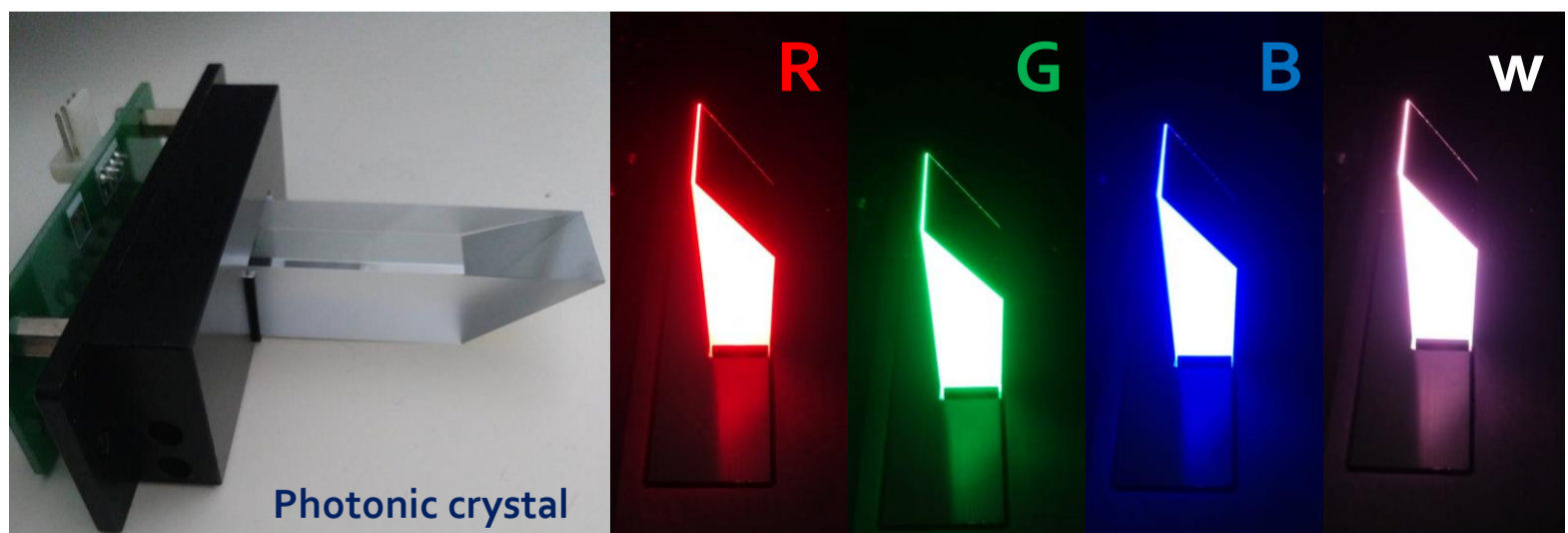
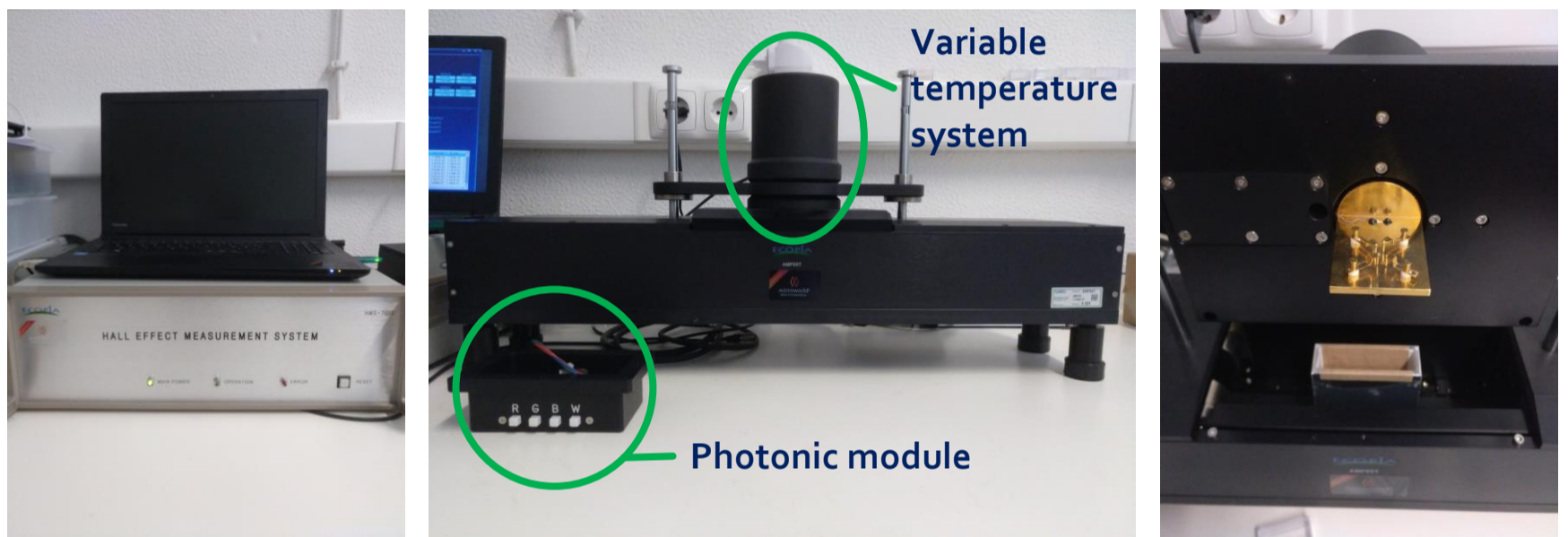


Hall Effect Measurement System

ELECTRICAL PROPERTIES MEASUREMENTS

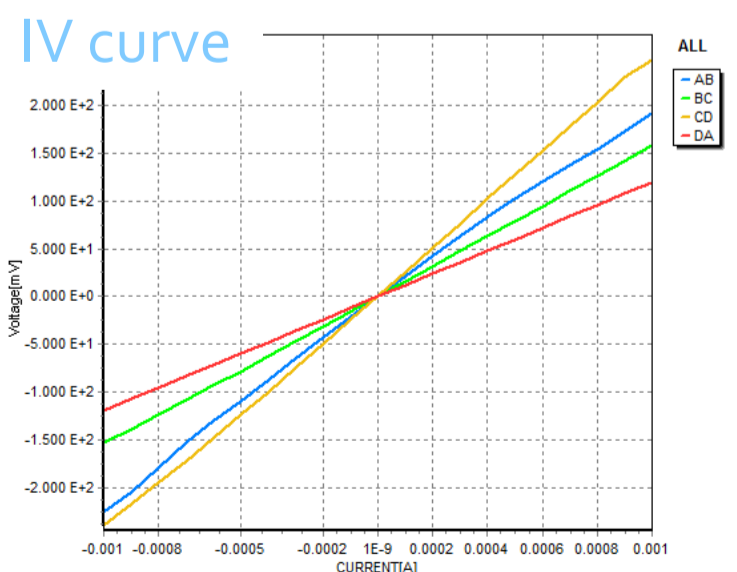
Determining the fundamental characteristics of a semiconductor is an important step when developing a specific device. **HALL EFFECT** technique allows the user to measure parameters such as carrier concentration, mobility, hall coefficient, etc. This technique reads the voltage difference between two diagonally opposed contacts when a flowing current and a fixed magnetic field are applied to the sample. Another possibility is to measure the same parameters under the influence of different wavelengths (**PHOTONIC HALL EFFECT**), a very useful technique for applications such as solar cells, optical sensors or thermoelectric materials (e.g. variation of the carrier concentration with incident wavelength).

ECOPIA HMS-7000 WITH AMP55T MODULE



Hall Effect measurement system full tech specs

- Current range: 10 nA – 999 mA
- Module SH80350K for low temperature measurements
- Temperature range: 80 – 350 K
- 4 programmable irradiation sources (RGBW)
- Analysis software with user friendly interface



Thin films Characterisation